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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/670,194	09/26/2003	Toshio Kimura	1035-471	4479

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NIXON & VANDERHYE, PC
901 NORTH GLEBE ROAD, 11TH FLOOR
ARLINGTON, VA 22203

EXAMINER	
IM, JUNGHWA M	

ART UNIT	PAPER NUMBER
2811	

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Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Office Action Summary	Application No.	Applicant(s)	
	10/670,194	KIMURA ET AL.	
	Examiner	Art Unit	
	JUNGHWA M. IM	2811	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE *3* MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

1)☒ Responsive to communication(s) filed on *02 July 2008*.

2a)☒ This action is **FINAL**. 2b)☐ This action is non-final.

3)☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

4)☒ Claim(s) *1-4,7-10 and 19-23* is/are pending in the application.

4a) Of the above claim(s) _____ is/are withdrawn from consideration.

5)☐ Claim(s) _____ is/are allowed.

6)☒ Claim(s) *1-4,7-10 and 19-23* is/are rejected.

7)☐ Claim(s) _____ is/are objected to.

8)☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

9)☐ The specification is objected to by the Examiner.

10)☒ The drawing(s) filed on *26 September 2003* is/are: a)☒ accepted or b)☐ objected to by the Examiner.

Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).

Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).

11)☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

12)☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).

a)☒ All b)☐ Some * c)☐ None of:

1.☒ Certified copies of the priority documents have been received.

2.☐ Certified copies of the priority documents have been received in Application No. _____.

3.☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

1) ☐ Notice of References Cited (PTO-892)
2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3) ☐ Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date _____.
4) ☐ Interview Summary (PTO-413) Paper No(s)/Mail Date. _____.
5) ☐ Notice of Informal Patent Application
6) ☐ Other: _____.

DETAILED ACTION

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

> (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 1, 3, 7 and 19-23 are rejected under 35 U.S.C. 103(a) as being unpatentable over Tomita et al. (US 5191405), hereinafter Tomita in view of Iwamoto (US Pub. 20030017654)

Regarding claim 1, Fig. 1h of Tomita shows a chip-stack semiconductor device, comprising:

multiple semiconductor chips [1, 6, 15, 23] vertically stacked on top of each other, wherein:

each of the semiconductor chips includes electrode pads [3, 4, 11, 24, 25, 26], and

multiple through electrodes [9, 22, 27] formed in a region of the electrode pads.

Tomita shows most aspects of the instant invention except "at least one type of the through electrodes of electrically conductive material is a non-contact through electrode that is not electrically connected to an electrode pad of the semiconductor chip in which the non-contact through electrode is formed." Fig. 16 of Iwamoto shows at least one type of the electrodes is a non-contact electrode [4d, 6d] that is not electrically connected to an electrode pad of the semiconductor chip. It would have been obvious

to one of ordinary skill in the art at the time of the invention was made to incorporate the teachings of Iwamoto into the device of Tomita in order to have at least one type of the through electrodes being a non-contact through electrode that is not electrically connected to an electrode pad of the semiconductor chip to provide added support.

Regarding claim 3, Fig. 1h of Tomita shows that at least one type of the through electrodes (the one connected from the layer 1) is contact through electrodes electrically connected to the electrode pad.

Regarding claim 7, Fig. 16 of Iwamoto shows that an electrode is further provided in regions outside of the electrode pad (6b).

Regarding claim 19, Fig. 1h of Tomita shows that the electrode pads are electrically connected with a device region of the semiconductor chip.

Regarding claim 20, Fig. 1h of Tomita shows a chip-stack semiconductor device, comprising:

multiple semiconductor chips [1, 6, 15, 23] vertically stacked on top of each other, and at least first [25 on the chip 23] and second electrode pads [24, 46] provided on at least one of the semiconductor chips wherein:

each of the semiconductor chips includes through electrodes [9, 22, 27] connected to each other in regions inside of electrode pads, each of through electrodes linking a front surface to a back surface of the semiconductor chip; and

each of the semiconductor chips includes multiple through electrodes [3, 4, 11, 24, 25, 26] wherein a plurality of different through electrodes are located inside of the first electrode pad.

Tomita shows most aspects of the instant invention except "at least one type of the through electrodes of electrically conductive material is a non-contact through electrode that is not electrically connected to an electrode pad of the semiconductor chip in which the non-contact through electrode is formed." Fig. 16 of Iwamoto shows at least one type of the electrodes is a non-contact electrode [4d] that is not electrically connected to an electrode pad of the semiconductor chip. It would have been obvious to one of ordinary skill in the art at the time of the invention was made to incorporate the teachings of Iwamoto into the device of Tomita in order to have at least one type of the through electrodes being a non-contact through electrode that is not electrically connected to an electrode pad of the semiconductor chip to provide added support.

Regarding claim 21, Fig. 1h of Tomita shows a plurality of different through electrodes (the one from the layer 1 and the one from the layer 15) provide in the first electrode pad 925), first and second of these different through electrodes carry different signals.

Regarding claim 22, Fig. 1h of Tomita shows a plurality of different through electrodes (the one from the layer 1 and the one from the layer 15) provide in the first electrode pad [25], first and second of these different through electrodes carry different signals.

Regarding claim 23, Fig. 1h of Tomita show a chip-stack semiconductor device comprising:

multiple semiconductor chips [1, 6, 15, 23] vertically stacked on top of each other, wherein each of the semiconductor chips includes electrode pads [3, 4, 11, 25],

and multiple through electrodes formed in a region within the electrode pads, wherein at least two of the through electrodes formed in a region within the same electrode pad [25] wherein the through electrodes are provided in respective apertures defined in the electrode pads so as to extend through the pads.

Tomita shows most aspects of the instant invention except "at least two of the through electrodes formed in a region within the same electrode pad are not in direct electrical contact with each other." Fig. 5 of Iwamoto shows at least one type of the through electrodes of electrically conductive material [4] is a non-contact electrode that is not electrically connected to an electrode pad of the semiconductor chip in which the non-contact through electrode is formed. It would have been obvious to one of ordinary skill in the art at the time of the invention was made to incorporate the teachings of Iwamoto into the device of Tomita in order to have at least two of the through electrodes within the same electrode pad not in direct electrical contact with each other for optional aril filled connection.

Claims 2, 4 and 8-10 are rejected under 35 U.S.C. 103(a) as being unpatentable over Tomita in view of Iwamoto as applied to claims 1 and 20 above further in view of Tsunashima (US 6087719).

Regarding claim 2, the combination of Tomita/Iwamoto shows most aspects of the instant invention except "at least one semiconductor chip the electrode pads are provided along a periphery of the semiconductor chip so as to surround a device region." Fig. 3B of Tsunashima shows a stacked semiconductor device wherein for at

least one semiconductor chip the electrode pads are provided along a periphery of the semiconductor chip so as to surround a device region. It would have been obvious to one of ordinary skill in the art at the time of the invention was made to incorporate the teachings of Tsunashima into the device of Tomita/Iwamoto in order to have the electrode pads along a periphery of the semiconductor chip for electrical connection to an outer device.

Regarding claim 4, Fig. 1h of Tomita shows that at least one type of the through electrodes (the one connected from the layer 1) is contact through electrodes electrically connected to the electrode pad.

Regarding claim 8, Fig. 5 of Iwamoto shows that a through electrode is further provided in regions outside of the electrode pad.

Regarding claims 9-10, Fig. 1h of Tomita shows most aspects of the instant invention except "the through electrodes in the semiconductor chips are connected to each other via bumps so that the semiconductor chips are vertically stacked on top of each other." Fig. 1 of Tsunashima shows that the through electrodes in the semiconductor chips are connected to each other via bumps [9] so that the semiconductor chips are vertically stacked on top of each other. It would have been obvious to one of ordinary skill in the art at the time of the invention was made to incorporate the teachings of Tsunashima into the device of Tomita in order to have the through electrodes in the semiconductor chips connected to each other via bumps to secure the connection

Response to Arguments

Applicant's arguments filed 7/5/2008 have been fully considered but they are not persuasive.

Applicants argue that "... it is clear that supporting member 4 is not an electrode. Instead, it is a structural member that is used to ensure that the tape substrate 5 remains planar after the thermal compression process. This is why the structural member 4 is not in contact with any electrodes on the tape substrate 5, unlike electrodes 3, each of which is in contact with a corresponding land electrode 6 on the tape substrate." This is not persuasive. Note that Iwamoto is referred to complement the limitation "a non-contact through electrode that is not electrically connected to an electrode pad of the semiconductor chip." Fig. 16 of Iwamoto shows a dummy land electrode (6b), implying that the electrode (6b) is not electrically connected to an electrode pad of the semiconductor chip. And each of the bumps (4d) is corresponds to one of the dummy electrodes (6b). Further, note that the instant invention discloses that the non--contact through electrodes are merely intermediaries between the vertically stacked chips.

Applicants argue that "In addition, supporting member 4 is not formed in a region within an electrode pad. In Fig. 1 of Iwamoto, electrode pads are labeled '2'. Iwamoto does not teach that the supporting members 4 are formed on electrode pads. Therefore, Iwamoto fails to teach 'multiple electrically conductive through electrodes formed in a region within the electrode pads, wherein at least one type of the through electrodes is a non-contact through electrode.' Moreover, it would not have been obvious to combine

Tomita and Iwamoto. Whereas, Tomita's device comprises a stacked semiconductor device having multiple semiconductor chips vertically stacked and connected via through electrodes, Iwamoto's device comprises a single semiconductor chip, without any need for through electrodes." Examiner disagrees. Note that Tomita shows most aspects of the instant invention including "a stacked semiconductor device having multiple semiconductor chips vertically stacked and connected via through electrodes" and "multiple electrically conductive through electrodes formed in a region within the electrode pads." Iwamoto is further referred to complement the limitation for a non-contact through electrode. Therefore, the combination of Tomita/ Iwamoto would show a vertically stacked semiconductor device having stacked multiple semiconductor chips and connected via through electrodes that are formed in a region within the electrode pads, wherein at least one type of the through electrodes is a non-contact through electrode.

Conclusion

THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any

extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to JUNGHWA M. IM whose telephone number is (571)272-1655. The examiner can normally be reached on MON.-FRI. 7:30AM-4:00PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Lynne A. Gurley can be reached on (571) 272-1670. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

/Lynne A. Gurley/
Supervisory Patent Examiner, Art Unit 2811
/J. M. I./
Examiner, Art Unit 2811